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1 Recognizing facial actions using Gabor wavelets with neutral face average difference Bazzo, J.J.; Lamar, M.V.; Automatic Face and Gesture Recognition, 2004. Proceedings. Sixth IEEE International Conference on , 17-19 May 2004		
Pages: 505 - 510		
[Abstract] [PDF Full-Text (1478 KB)] IEEE CNF		
2 A feature space for face image processing Qing Song; Robinson, J.; Pattern Recognition, 2000. Proceedings. 15th International Conference on, Volume: 2, 3-7 Sept 2000 Pages: 97 - 100 vol. 2 [Abstract] [PDF Full-Text (864 KB)] IEEE CNF		

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Proceedings	Bazzo, J.J. Lamar, M.V.	
O- Standards	Dept. of Electr. Eng., Fed. Univ. of Parana, Curitiba, Brazil This paper appears in: Automatic Face and Gesture Recognition, 200	n 4
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O- By Author	Publication Date: 17-19 May 2004	
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